

Precision Monolithics Inc.

**1.0 SCOPE**

- 1.1 Scope.** This specification covers the detail requirements for a high-speed, low noise dual operational amplifier.

It is highly recommended that this datasheet be used as a baseline for new military or aerospace specification control drawings.

- 1.2 Part Number.** The complete part numbers per Table 1 of this specification follow:

<u>Device</u>	<u>Part Number</u>	<u>Package</u>
A	OP-270AZ/883	Z
A	OP-270ARC/883	RC

- 1.2.3 Case Outline.** The case outline is designated as follows:

<u>Letter</u>	<u>Case Outline</u> (Lead Finish per MIL-STD-38510)
Z	8-lead ceramic dual-in-line package
RC	20-pin leadless chip carrier

- 1.3 Absolute Maximum Ratings. ( $T_A = +25^\circ\text{C}$ , unless otherwise noted)**

Supply Voltage .....	$\pm 18\text{V}$
Differential Input Voltage (Note 1) .....	$\pm 1\text{V}$
Differential Input Current (Note 1) .....	$\pm 25\text{mA}$
Input Voltage .....	Supply Voltage
Output Short-Circuit Duration .....	Continuous
Storage Temperature Range .....	-65°C to +150°C
Operating Temperature Range .....	-55°C $\leq T_A \leq$ +125°C
Lead Temperature Range (Soldering, 60 sec) .....	300°C
Maximum Junction Temperature ( $T_J$ ) .....	150°C

**NOTE:**

1. The OP-270's inputs are protected by back-to-back diodes. Current limiting resistors are not used in order to achieve low noise performance. If the differential input voltage exceeds  $\pm 1.0\text{V}$ , the input current should be limited to  $\pm 25\text{mA}$ .

**1.5 Thermal Characteristics:**

Thermal Resistance, CERDIP (Z) package: Junction-to-Case ( $\Theta_{JC}$ ) = 45°C/W MAX  
 Junction-to-Ambient ( $\Theta_{JA}$ ) = 150°C/W MAX

Thermal Resistance, LCC (RC) package: Junction-to-Case ( $\Theta_{JC}$ ) = 35°C/W MAX  
 Junction-to-Ambient ( $\Theta_{JA}$ ) = 110°C/W MAX



TABLE 1

 $V_S = \pm 15V$ ;  $R_S = 50\Omega$ ;  $T_J = T_A = +25^\circ C$  unless otherwise specified.
OP-270/883  
LIMITS A

Characteristic	Symbol	Special Conditions	MIN	MAX	Units
Input Offset Voltage	$V_{OS}$	$-55^\circ \leq T_A \leq +125^\circ C$	--	75	$\mu V$
Input Offset Current	$I_{OS}$	$V_{CM} = 0V$ $-55^\circ \leq T_A \leq +125^\circ C$	--	10	nA
Input Bias Current	$I_B$	$V_{CM} = 0V$ $-55^\circ \leq T_A \leq +125^\circ C$	--	30	nA
Input Noise Voltage	$E_{nt}$	$f_O = 1Hz$ to $100Hz$ see test circuit	--	80	$nV_{RMS}$
Large-Signal Voltage Gain	$A_{vO}$	$V_O = \pm 10V$ $R_L = 10k\Omega$	1500	--	$V/mV$
		$V_O = \pm 10V$ $R_L = 10k\Omega$ $-55^\circ \leq T_A \leq +125^\circ C$	750	--	$V/mV$
		$V_O = \pm 10V$ $R_L = 2k\Omega$	750	--	$V/mV$
		$V_O = \pm 10V$ $R_L = 2k\Omega$ $-55^\circ \leq T_A \leq +125^\circ C$	400	--	$V/mV$
		$R_L = 2k\Omega$ $-55^\circ \leq T_A \leq +125^\circ C$	$\pm 12$	--	V
Output Voltage Swing	$V_O$	$R_L = 2k\Omega$ $-55^\circ \leq T_A \leq +125^\circ C$	$\pm 12$	--	V
Common-Mode Rejection (Note 1)	CMR	$V_{CM} = \pm 12V$	106	--	dB
		$V_{CM} = \pm 12V$ $-55^\circ \leq T_A \leq +125^\circ C$	100	--	dB

TABLE 1 $V_S = \pm 15V$ ;  $R_S = 50\Omega$ ;  $T_J = T_A = +25^\circ C$  unless otherwise specified.

Characteristic	Symbol	Special Conditions	OP-270/883 <u>LIMITS A</u>		Units
			MIN	MAX	
Power-Supply Rejection Ratio	PSRR	$V_S = \pm 4.5V$ to $\pm 18V$ $V_S = \pm 4.5V$ to $\pm 18V$ $-55^\circ \leq T_A \leq +125^\circ C$	--	3.2 5.6	$\mu V/V$ $\mu V/V$
Supply Current (Note 2)	$I_{SY}$	No Load No Load $-55^\circ \leq T_A \leq +125^\circ C$	-- --	6.5 7.5	mA mA
Slew Rate	SR	$A_{VCL} = +20$ , $R_L = 10k\Omega$	$\pm 1.7$	--	V/ $\mu s$
Input Offset Voltage Temperature Coefficient	$TCV_{OS}$	$-55^\circ \leq T_A \leq +125^\circ C$	--	1.0	$\mu V/^\circ C$

Note 1. IVR is defined as the  $V_{CM}$  range used for the CMR test.Note 2.  $I_{SY}$  limit = total for both amplifiers.

**PMI****TABLE 2****OP-270/883****Electrical Test Requirements  
For Class B Devices**

---

MIL-STD-883 Test Requirement	Subgroups (see Table.3)
Interim Electrical Parameters (pre Burn-In)	1
Final Electrical Test Parameters	1*, 2, 3,4,5,6
Group A Test Requirements	1,2,3,4,5,6,7,8

---

\* PDA applies to Subgroup 1 only.  
No other Subgroups are included in PDA.

PMI

**TABLE 3**  
**Group A Inspection** $V_S = \pm 15V$ ;  $R_S = 50\Omega$ ;  $T_J = T_A$  unless otherwise specified.

		OP-270/883 <u>LIMITS A</u>		
Symbol	Special Conditions	MIN	MAX	Units
<b>Subgroup 1.</b> $T_A = +25^\circ C$	$V_{OS}$	--	75	$\mu V$
	$I_{OS} \quad V_{CM} = 0V$	--	10	nA
	$I_B \quad V_{CM} = 0V$	--	20	nA
	CMR $V_{CM} = \pm 12V$	106	--	dB
	PSRR $V_S = \pm 4.5V$ to $\pm 18V$	--	3.2	$\mu V/V$
	$I_{SY}$ No Load (Note 1)	--	6.5	mA
<b>Subgroup 2.</b> $T_A = +125^\circ C$	$V_{OS}$	--	175	$\mu V$
	$I_{OS} \quad V_{CM} = 0V$	--	30	nA
	$I_B \quad V_{CM} = 0V$	--	60	nA
	CMR $V_{CM} = \pm 12V$	100	--	dB
	PSRR $V_S = \pm 4.5V$ to $\pm 18V$	--	5.6	$\mu V/V$
	$I_{SY}$ No Load (Note 1)	--	7.5	mA

**TABLE 3**  
**Group A Inspection**

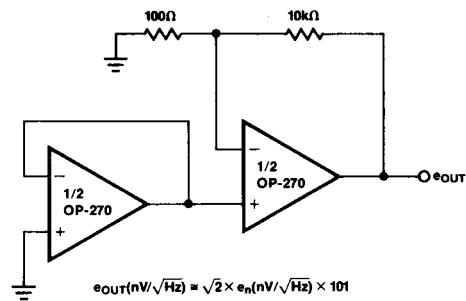
$V_S = \pm 15V$ ;  $R_S = 50\Omega$ ;  $T_J = T_A$  unless otherwise specified.

Symbol	Special Conditions	<b>OP-270/883 LIMITS A</b>		<b>Units</b>
		<b>MIN</b>	<b>MAX</b>	
<b>Subgroup 3.</b> $T_A = -55^\circ C$	All Tests, Limits and Conditions are the same as for Subgroup 2.			
<b>Subgroup 4.</b> $T_A = +25^\circ C$	$A_{V_O}$ $V_O = \pm 10V, R_L = 10k\Omega$ $V_O = \pm 10V, R_L = 2k\Omega$	1500	--	V/mV
	$V_O$ $R_L = 2k\Omega$	750	--	V/mV
<b>Subgroup 5.</b> $T_A = +125^\circ C$	$A_{V_O}$ $V_O = \pm 10V, R_L = 10k\Omega$ $V_O = \pm 10V, R_L = 2k\Omega$	750	--	V/mV
	$V_O$ $R_L = 2k\Omega$	400	--	V/mV
<b>Subgroup 6.</b> $T_A = +55^\circ C$	All Tests, Limits and Conditions are the same as for Subgroup 5.	$\pm 12$	--	V
<b>Subgroup 7.</b> $T_A = +25^\circ C$	$SR$ $A_{VCL} = +20$ $R_L = 10k\Omega$	$\pm 1.7$	--	V/ $\mu$ s
	$E_{nt}$ $f_O = 1Hz$ to $100Hz$	--	80	nV <sub>RMS</sub>
<b>Subgroup 8.</b> $T_A = -55^\circ C, +125^\circ C$	$TCV_{OS}$	--	1.0	$\mu V/^{\circ}C$

Note 1.  $I_{SY}$  limit = total of both amplifiers.

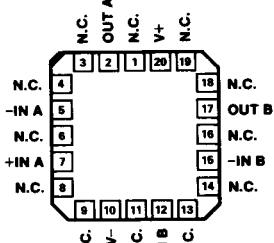
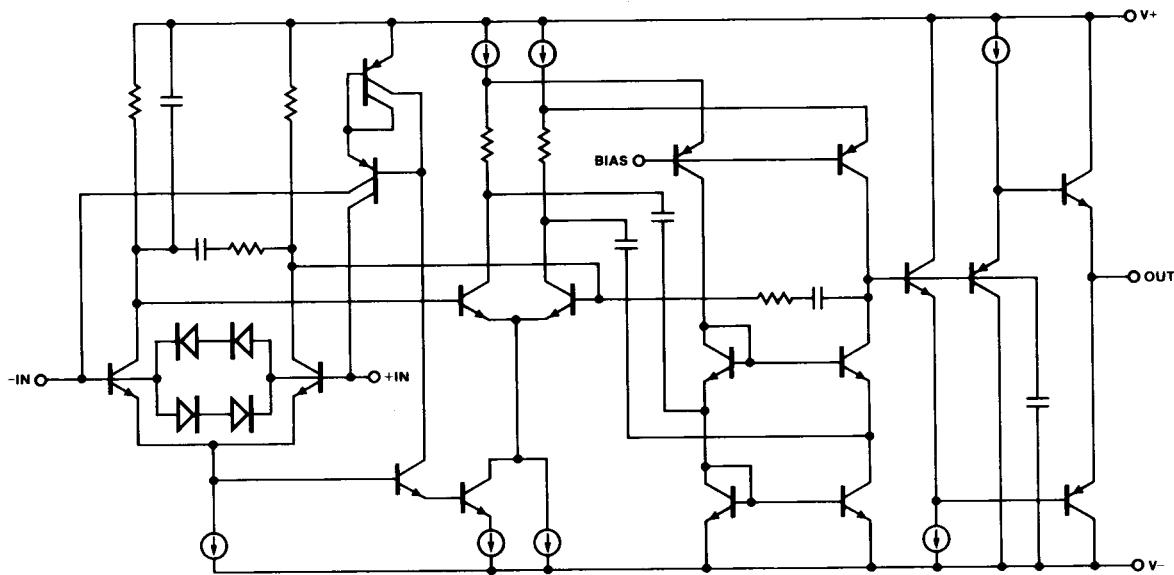
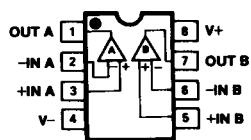
PMI

## Noise Test Circuit Schematic



5

## 3.2.1 Simplified Schematic and Pin Connections

LCC  
(RC-Suffix)8-PIN HERMETIC DIP  
(Z-Suffix)

**[PMI]**

---

**3.2.4 Microcircuit Group Assignment.** This microcircuit is covered by microcircuit group 49.

**4.2 Life Test/Burn-In Circuit.**

Burn-in performed per 883/1005 condition A, B, C, or D.